

First Announcement and Call for Papers

CIE EXPERT SYMPOSIUM
on
Advances in Photometry and Colorimetry

7-8 July 2008, Turin (Torino), Italy



Background

This Symposium will focus on recent research and developments in physical photometry and colorimetry, with a focus on applications of imaging luminance measurement devices, including near-field goniophotometers, for measurement of light sources, luminaires, displays, and lighting environments. Another focus will be on the measurement of spectral characteristics of photometers and colorimeters, including the degree of the $V(\lambda)$ match (the f_1'), whose uncertainty is often questioned. Other topics of new developments in physical photometry and colorimetry will also be covered. The meeting is organized by CIE Division 2 and hosted by INRIM (Istituto Nazionale di Ricerca Metrologica) in Turin, Italy. There will be CIE Division 2 meetings in conjunction with this Symposium.

Goals

To discuss and summarize the state of the art of recent developments in physical photometry and colorimetry, with special emphasis on applications of imaging devices for photometry and colorimetry, and measurements of spectral characteristics of photometers and colorimeters. The outcomes of the symposium will be utilized as recommendations for future work in Division 2.

Who should attend

This meeting is open to everyone with an interest in any aspect of physical photometry and colorimetry, thus measurement of visible radiation and color. Early registration is recommended to ensure adequate space and support, and to allow adequate distribution and review of relevant documents.

Venue

The exact location of the symposium (a hotel in Turin or INRIM), together with other local area information, will soon be announced.

Call for papers

The two-day Symposium will feature Invited Papers and Contributed Papers. Ample time will be secured for round-table discussions. Poster session may be held depending on number of papers received.

Papers should deal with one of the following subjects:

- Characterization and/or improvements of imaging photometers and colorimeters
- Applications of imaging luminance measurement devices for photometry and colorimetry (for light sources, displays, luminaires, etc.)
- Measurement of spectral responsivity and f_1' of photometers / colorimeters and uncertainty evaluation
- Other developments of new techniques in photometry and colorimetry, including improvements in spectroradiometry (for photometry and colorimetry) and object color measurement

Authors are invited to submit two-page extended abstracts of their proposed contributions in English **no later than 28 February 2008** by e-mail or mail to

CIE Central Bureau
Kegelgasse 27, A-1030 Vienna, Austria
E-mail: symposium@cie.co.at

Authors will be notified of acceptance of their abstract by **1 April 2008**. The submitted extended abstracts, if accepted, will be printed in the Abstract booklet, which will be distributed at the Symposium. Accepted authors will be requested to submit a full paper (maximum 6 pages) for the Proceedings. Instructions for preparing camera-ready papers will be distributed to the authors after acceptance of abstracts. **Final camera-ready papers are due at the Symposium**. The proceedings of the Symposium will be made available after the meeting.

Accepted Symposium contributions will be pre-published for Symposium participants on the Symposium website.

Related meeting

A General meeting of Division 2 (Physical Measurement of Light and Radiation) as well as Technical Committee meetings will take place July 9-11, 2008, immediately following the Symposium; details are to be announced.

Symposium website

Further information of the Symposium including registration forms will be available at

www.inrim.it/CIE2008

Pre-registration

To receive the 2nd announcement and further information by email, please contact symposium@cie.co.at.

Organization

Symposium Co-Chairs

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